

Update of AFB measurement with $Z \rightarrow q\bar{q}$

Libo Liao

Gang LI, Weimin Song, Jin Zhang, Jiabao Gong, Jiarong Li, Yilun Wang, and Zhaoling Zhang

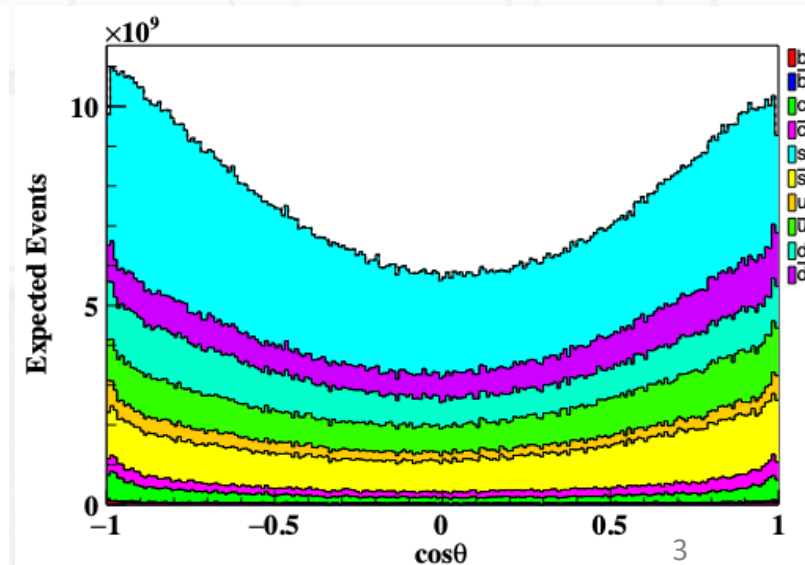
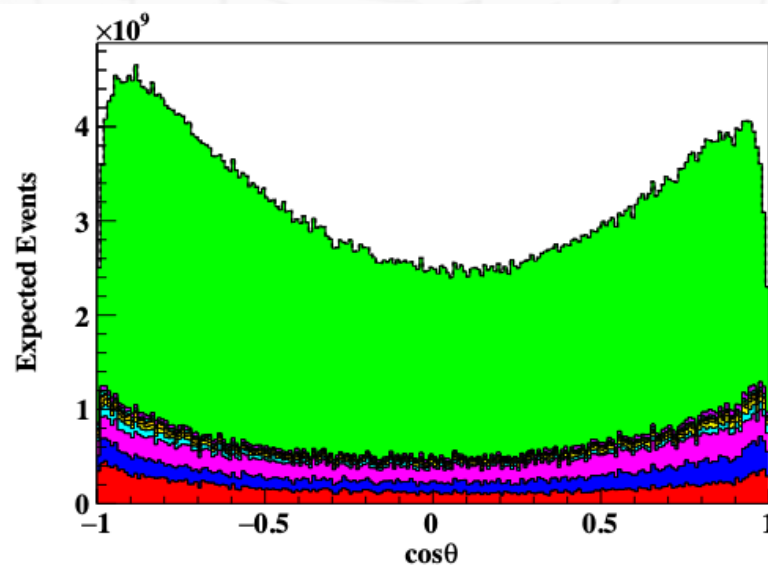
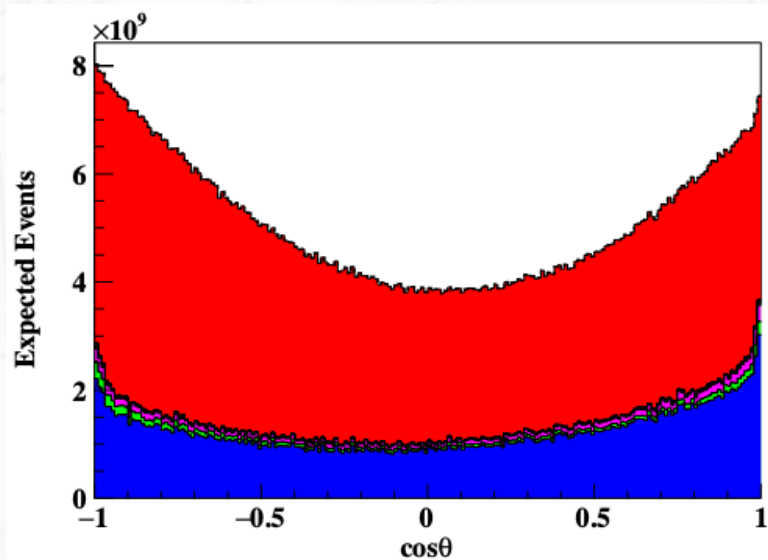
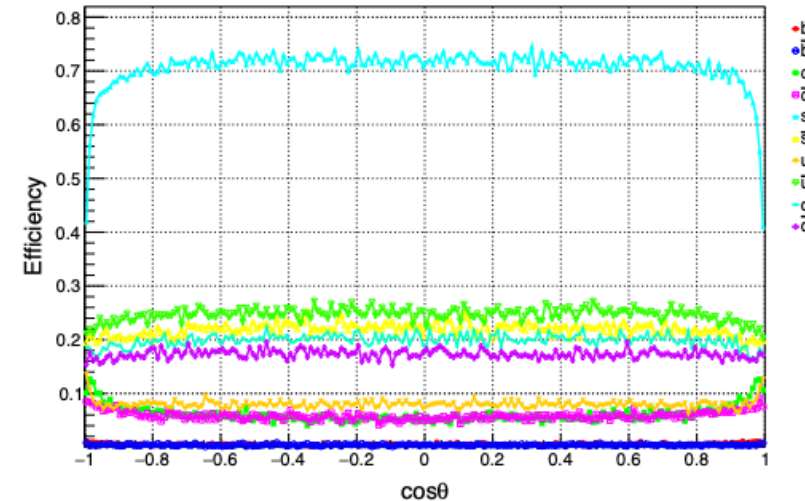
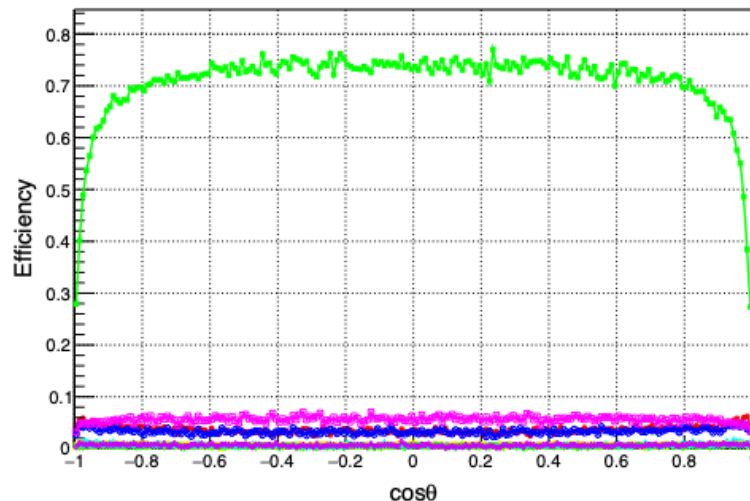
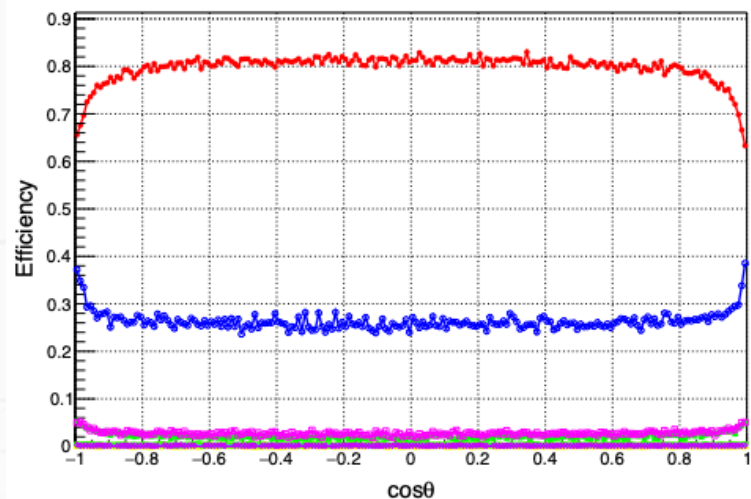


Outline

- Review of Prior Report
- Update
- Summary

Efficiency curves

Event selection -> Jet clustering -> ParticleNet -> Working point determination -> Efficiency curves



Measurement of A_{FB}

- The expected number of events for reconstructed flavor j (5 flavor) in bin i (200) is:

$$N_{i,j}^{\text{exp}} = \mathcal{L} \sum_k \sigma_{i,j} \epsilon_{i,j,k},$$

$$\sigma_{i,j} = (1 + \cos^2 \theta_i + \frac{8}{3} A_{FB,j} \cos \theta_i) \Delta,$$

- A_{FB} could be extracted via a binned maximum likelihood fit

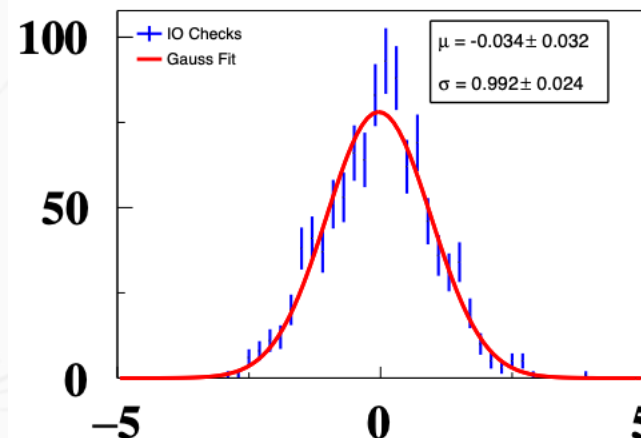
$$\mathcal{L}(A_{FB,j}, N_j^{\text{prod}}) = \prod_i \frac{\mu_{i,j}^{n_{i,j}} e^{-\mu_{i,j}}}{n_{i,j}!},$$

- To estimate the statistical precision, and joint flavor and charge identification

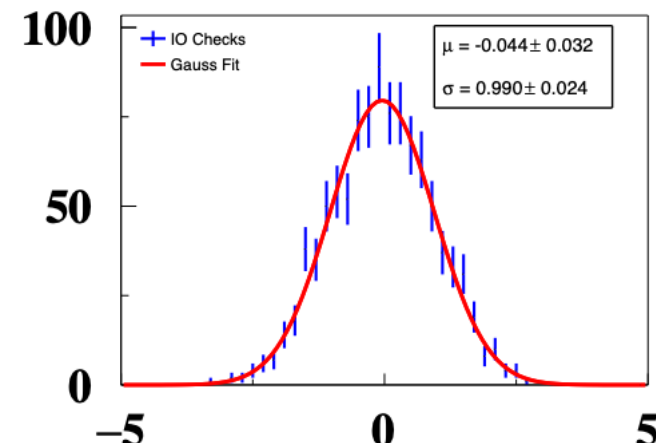
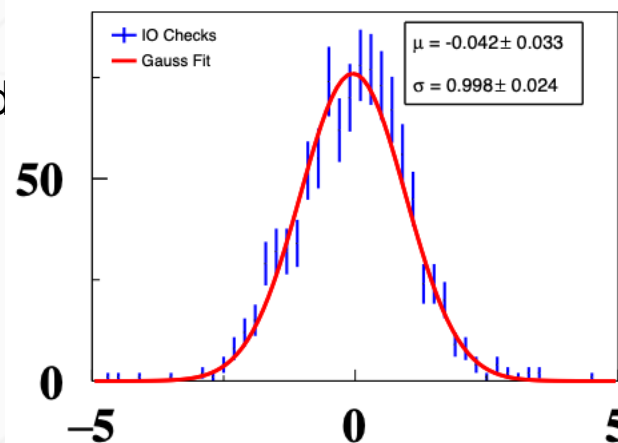
◆ Generate 1000 toy Monte Carlo samples.

- The results are listed below:

	This work (10^{-3})	PDG values(10^{-3})
ΔA_{FB}^b	0.013	16
ΔA_{FB}^c	0.021	50
ΔA_{FB}^s	0.018	148



$$\text{Pull} = (O - I) / \text{error}$$





Measurement of $\sin^2 \theta_W^{eff}$

- The published sensitivities of $\sin^2 \theta_{eff}^{lept}$ are at the 10^{-3} level
 - ◆ The sensitivity obtained from $A_{FB}^{0,b}$ is better than that from $A_{FB}^{0,l}$, because the cross section for quark final states is larger than that for leptonic decays.

	$\sin^2 \theta_{eff}^{lept}$	$\Delta \sin^2 \theta_{eff}^{lept} (10^{-3})$
LEP, $A_{FB}^{0,b}$	0.23221 ± 0.00029	1.3
LEP, $A_{FB}^{0,l}$	0.23099 ± 0.00053	2.3
SLC, A_{LR}	0.23098 ± 0.00026	1.2
LEP+SLC	0.23153 ± 0.00016	0.70

- To extract $\sin^2 \theta_W^{eff}$ from the simulated CEPC data, a similar binned extended maximum likelihood is performed
- 1000 toy Monte Carlo samples, pull distributions are also standard
- The results (10^{-6}) are listed
 - ◆ Improvements in both statistical precision and analysis methods

	b	c	s
$\Delta \sin^2 \theta_{eff}^{lept}$	1.0	1.5	1.4



Extension to polarization scenario

- The expected bin-by-bin number of left(right)-handed events

$$N_{L(R),i,j}^{\text{exp}} = \mathcal{L} \Delta \sum_k \sigma_{L(R),i,j} \epsilon_{i,j,k},$$

- $\sin^2 \theta_W^{\text{eff}}$ could be extracted via a binned maximum likelihood fit

$$\mathcal{L}(\sin^2 \theta_W^{\text{eff}}, N_{L,j}^{\text{prod}}, N_{R,j}^{\text{prod}}) = \prod_i \frac{\mu_{L,i,j}^{n_{L,i,j}} e^{-\mu_{L,i,j}}}{n_{L,i,j}!} \times \frac{\mu_{R,i,j}^{n_{R,i,j}} e^{-\mu_{R,i,j}}}{n_{R,i,j}!},$$

- 1000 toy Monte Carlo samples, pull distributions are also standard
- The results (10^{-6}) are listed

	$P_e = 0.5$	$P_e = 0.6$	$P_e = 0.7$	$P_e = 0.8$
b	0.55	0.54	0.52	0.51
c	0.71	0.69	0.68	0.65
s	0.83	0.82	0.81	0.79



Discussion of systematic uncertainties

- Detector modeling
- Flavor-tagging calibration
- Beam energy and polarization
- QCD and hadronization modeling
- Background contamination
- Beamstrahlung effects

Table 8. Summary of key systematic uncertainties.

Source	A_{FB}	$\sin^2 \theta_W^{\text{eff}}$
Beam energy	1.7×10^{-6}	1.0×10^{-6}
Luminosity	1.8×10^{-6}	3.4×10^{-7}
Polarization	-	1.7×10^{-5}
QCD corrections	10^{-4}	10^{-4}



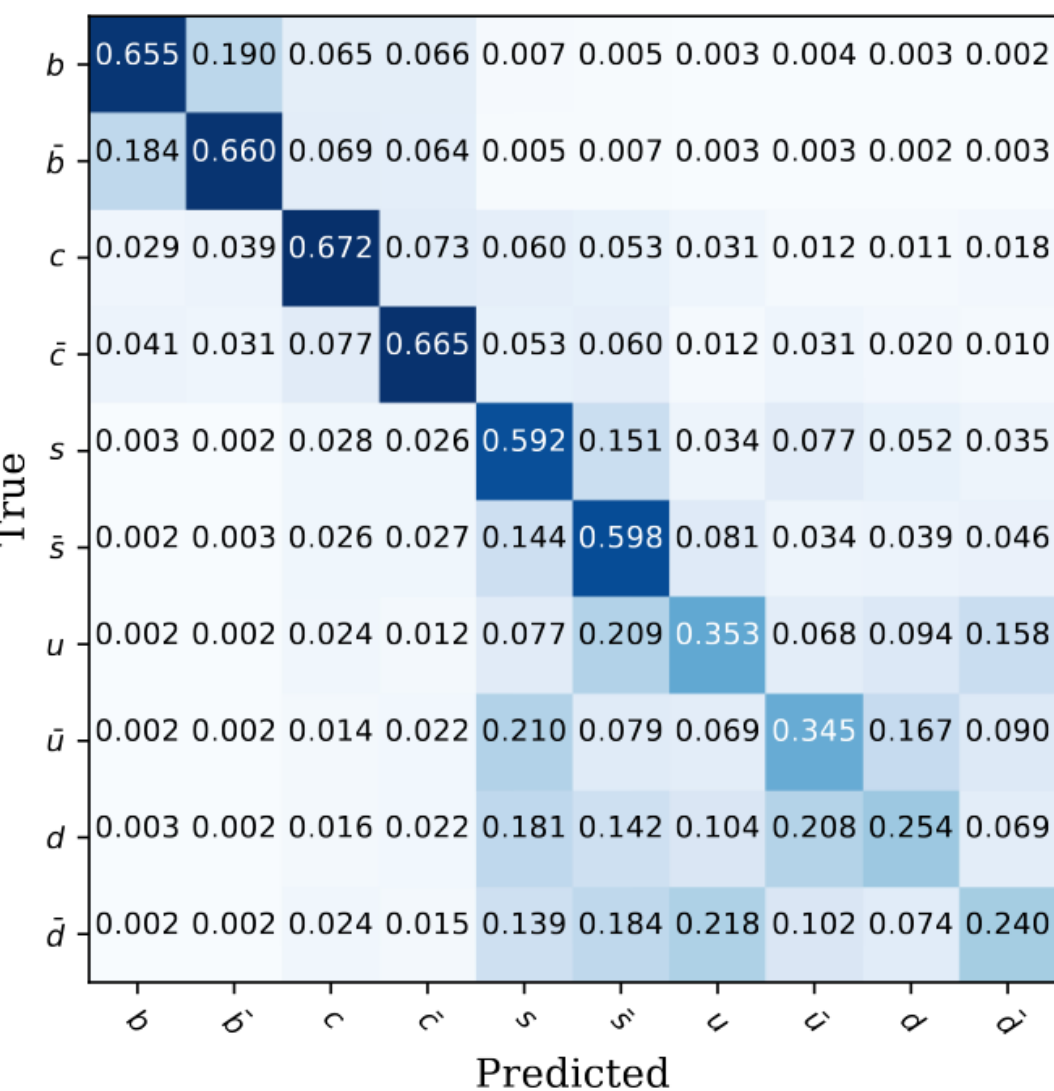
Outline



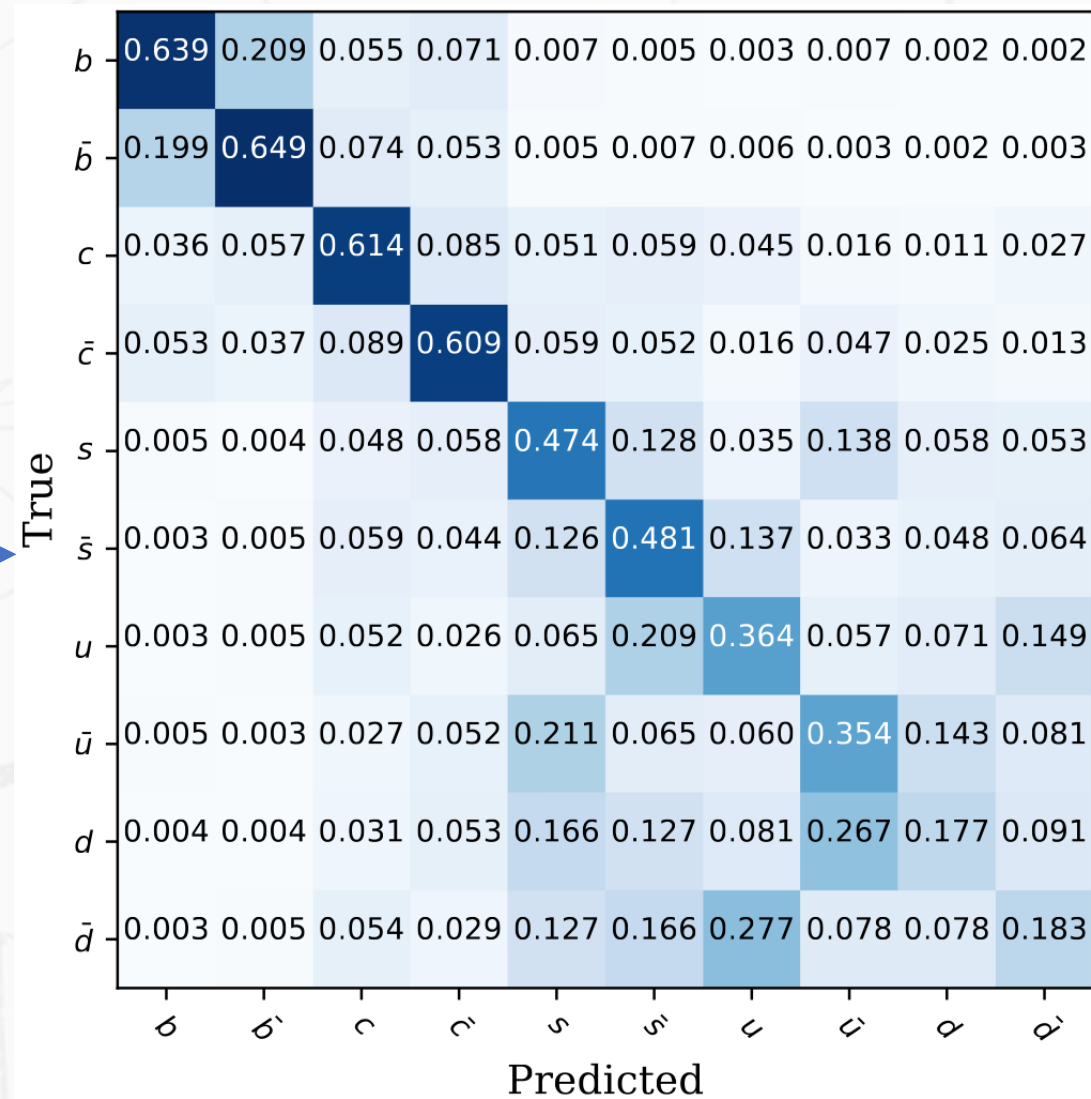
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➤ Update

Joint flavor and charge identification



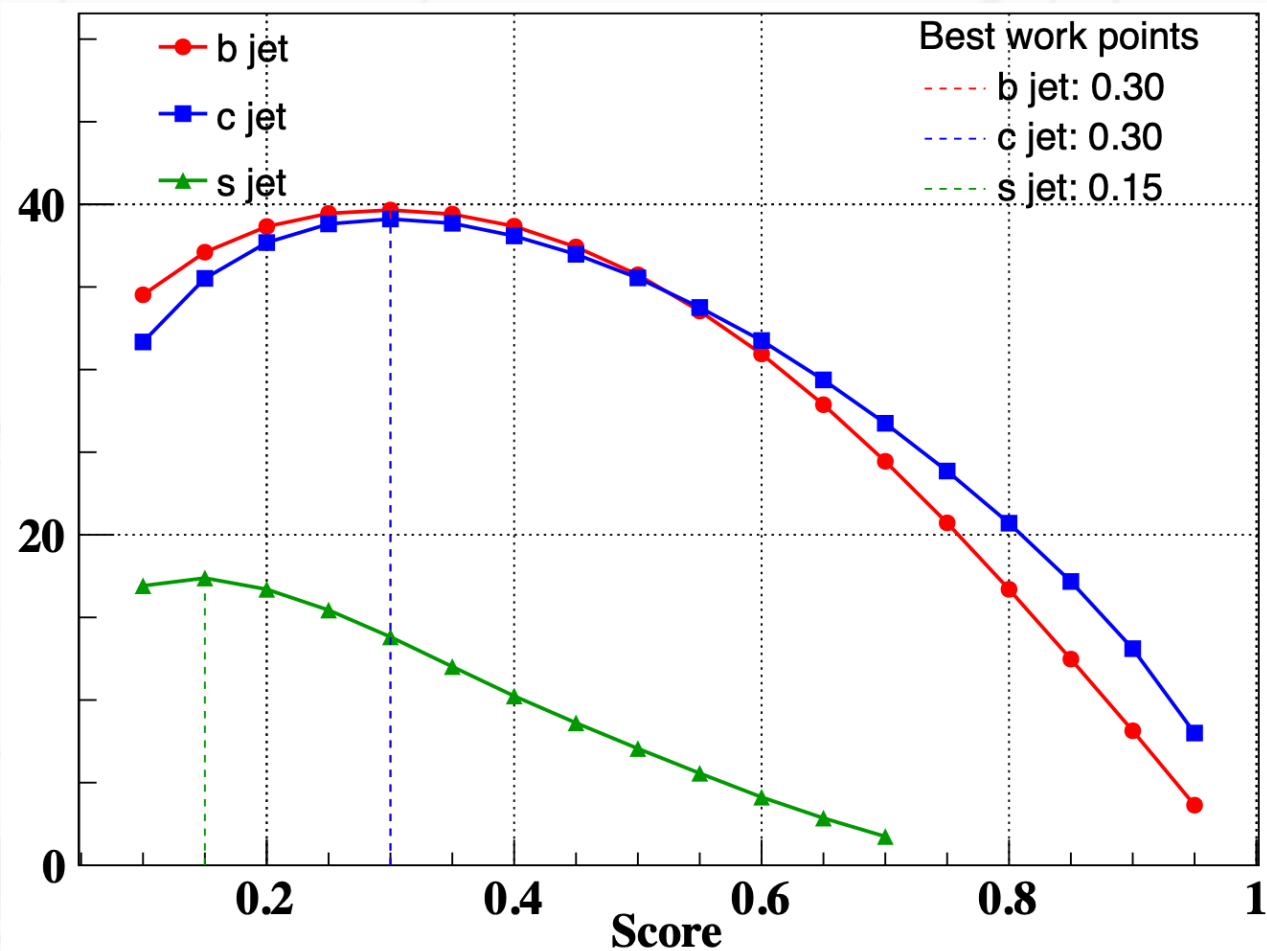
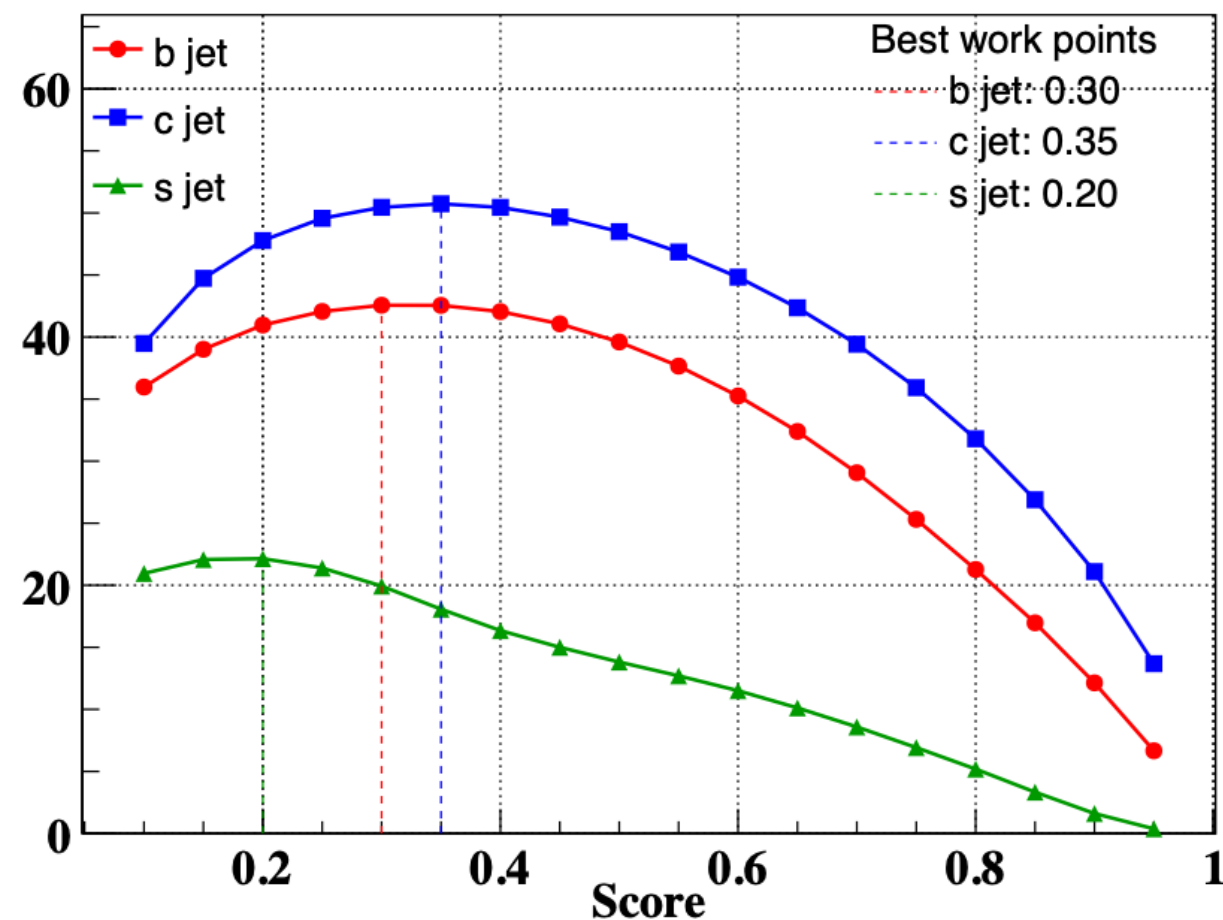
fast/full



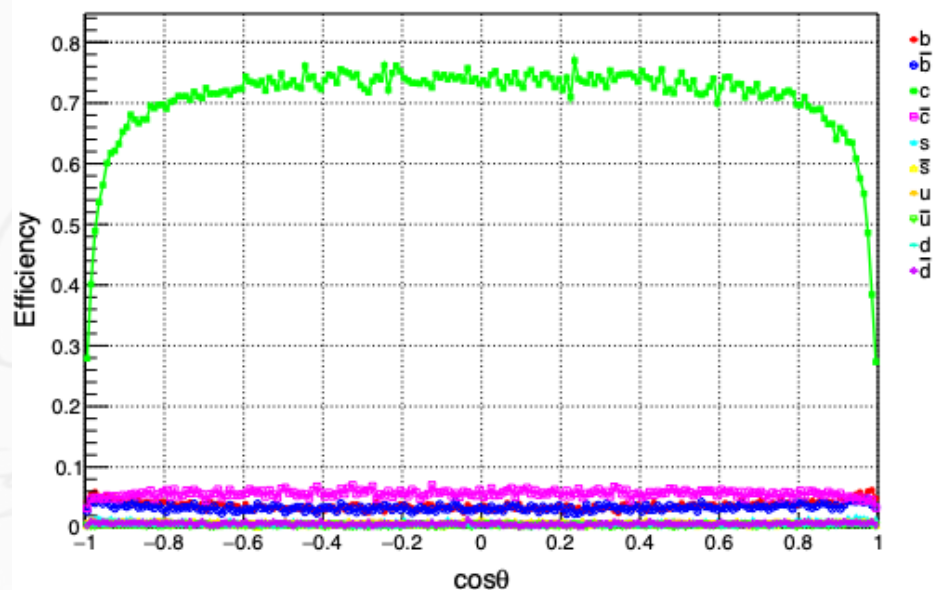
Determination of working points

$$\text{FoM} = \sum_i \sigma_i \times \epsilon_i \times \rho_i \times \left(\frac{1}{\sigma_i} \frac{\partial \sigma_i}{\partial A_{\text{FB}}} \right)^2$$
$$= \sum_i \epsilon_i \times \rho_i \times \frac{1}{\sigma_i} \left(\frac{8}{3} \cos \theta_i \right)^2,$$

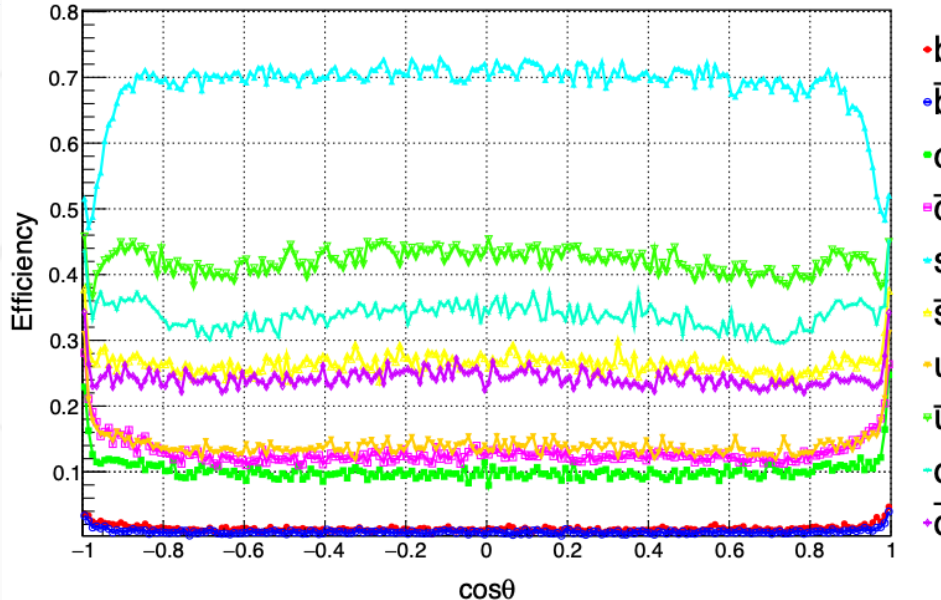
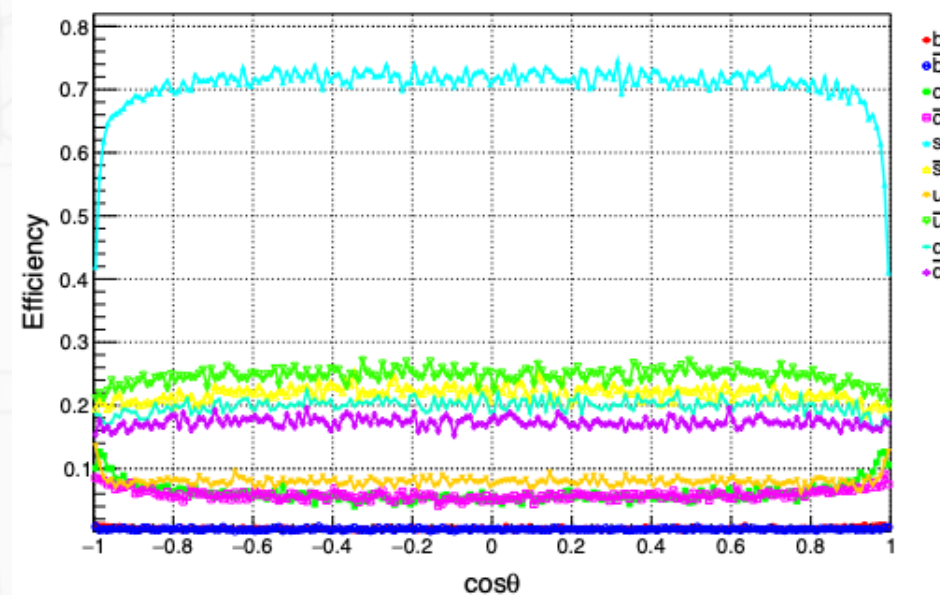
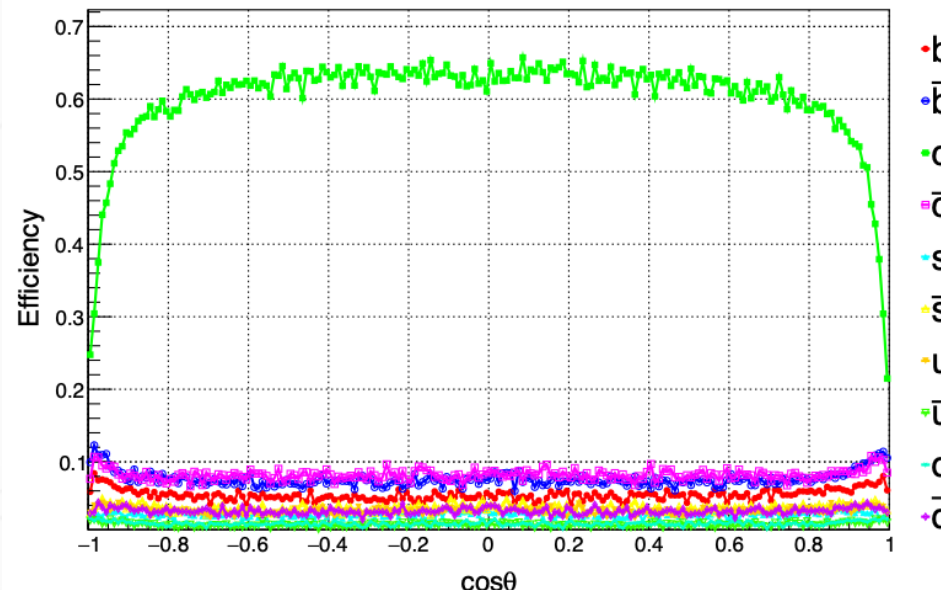
fast/full



Efficiency curves (c, s, as example)



fast/full





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- ◆ Generate 1000 toy Monte Carlo samples.

- The results are listed below:

	This work (10^{-3})	PDG values(10^{-3})
ΔA_{FB}^b	0.013(0.013)	16
ΔA_{FB}^c	0.021(0.026)	50
ΔA_{FB}^s	0.018(0.019)	148

- More sensitive to the signal efficiency than to the background efficiency.





Measurement of $\sin^2 \theta_W^{eff}$

- To extract $\sin^2 \theta_W^{eff}$ from the simulated CEPC data, a similar binned extended maximum likelihood is performed
- 1000 toy Monte Carlo samples, pull distributions are also standard
- The results (10^{-6}) are listed
 - ◆ Improvements in both statistical precision and analysis methods

	b	c	s
$\Delta \sin^2 \theta_{eff}^{lept}$	1.0(1.1)	1.5(1.9)	1.4(1.7)

Extension to polarization scenario

- The expected bin-by-bin number of left(right)-handed events

$$N_{L(R),i,j}^{\text{exp}} = \mathcal{L} \Delta \sum_k \sigma_{L(R),i,j} \epsilon_{i,j,k},$$

- $\sin^2 \theta_W^{\text{eff}}$ could be extracted via a binned maximum likelihood fit

$$\mathcal{L}(\sin^2 \theta_W^{\text{eff}}, N_{L,j}^{\text{prod}}, N_{R,j}^{\text{prod}}) = \prod_i \frac{\mu_{L,i,j}^{n_{L,i,j}} e^{-\mu_{L,i,j}}}{n_{L,i,j}!} \times \frac{\mu_{R,i,j}^{n_{R,i,j}} e^{-\mu_{R,i,j}}}{n_{R,i,j}!},$$

- 1000 toy Monte Carlo samples, pull distributions are also standard
- The results (10^{-6}) are listed

	$P_e = 0.5$	$P_e = 0.6$	$P_e = 0.7$	$P_e = 0.8$
b	0.55(0.62)	0.54(0.58)	0.52(0.57)	0.51(0.55)
c	0.71(0.91)	0.69(0.89)	0.68(0.86)	0.65(0.84)
s	0.83(0.98)	0.82(0.97)	0.81(0.95)	0.79(0.93)



Summary

- Fast simulation results are superseded by full simulation.
- The results are consistent with expected.
- The draft is ready, and we request to proceed to the next stage.